

ON Semiconductor®

FDS6673BZ P-Channel PowerTrench[®] MOSFET -30V, -14.5A, 7.8mΩ

General Description

This P-Channel MOSFET is produced using ON Semiconductor's advanced Power Trench process that has been especially tailored to minimize the on-state resistance.

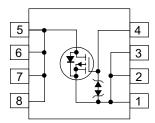
This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)} = 7.8 m\Omega$, $V_{GS} = -10V$, $I_D = -14.5A$
- Max $r_{DS(on)} = 12m\Omega$, $V_{GS} = -4.5V$, $I_D = -12A$
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 6.5kV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- RoHS compliant





MOSFET Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|--|---------|------------|-------|
| V _{DS} | Drain to Source Voltage | | -30 | V |
| V _{GS} | Gate to Source Voltage | | ±25 | V |
| I _D | Drain Current -Continuous (I | Note1a) | -14.5 | A |
| | -Pulsed | | -75 | A |
| P _D | Power Dissipation for Single Operation (| Note1a) | 2.5 | |
| | (| Note1b) | 1.2 | W |
| | (| Note1c) | 1.0 | |
| T _J , T _{STG} | Operating and Storage Temperature | | -55 to 150 | °C |

Thermal Characteristics

| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1a) | 50 | °C/W |
|---------------------|---|----|------|
| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction to Case (Note 1) | 25 | °C/W |

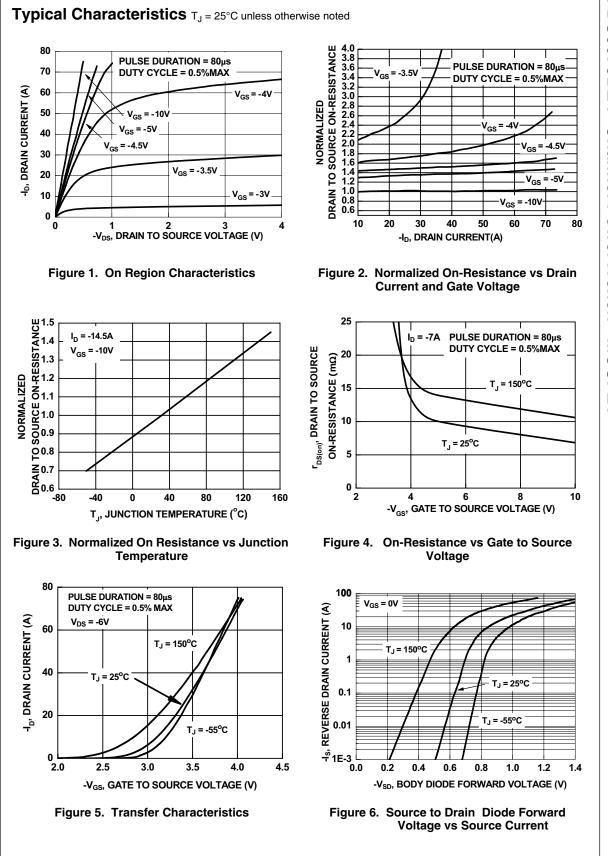
Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape Width | Quantity |
|----------------|-----------|-----------|------------|------------|
| FDS6673BZ | FDS6673BZ | 13" | 12mm | 2500 units |

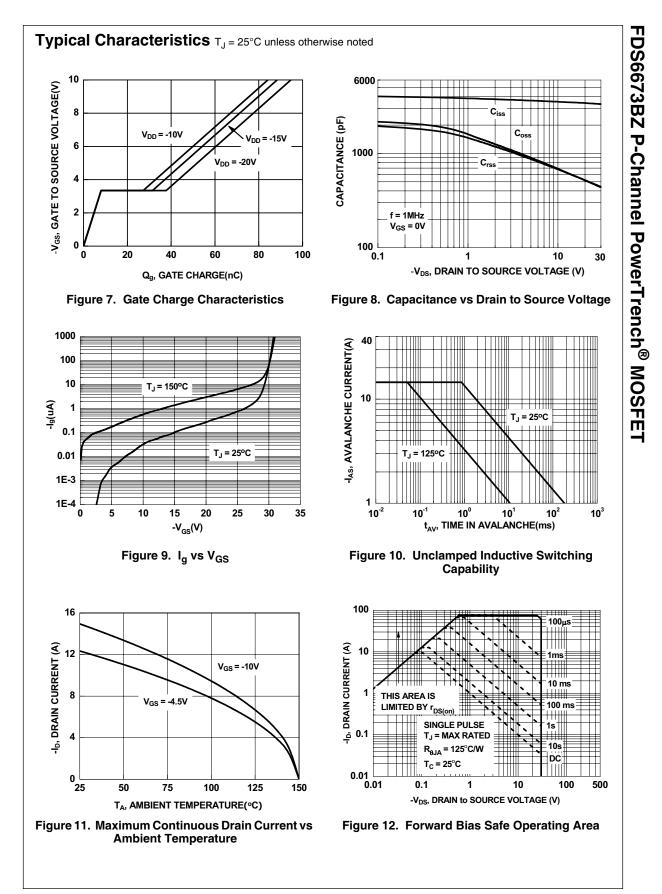
| B _{VDSS} ΔB _{VDSS} ΔT _J I _{DSS} I _{GSS} On Chara | cteristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current cteristics (Note 2) | $\begin{split} I_{D} &= -250 \mu A, \ V_{GS} = 0 V \\ I_{D} &= -250 \mu A, \ referenced \ to \\ 25^{\circ}C \\ V_{DS} &= -24 V, \ V_{GS} = 0 V \\ V_{GS} &= \pm 25 V, \ V_{DS} = 0 V \end{split}$ | -30 | | | |
|---|--|---|-----|---|--------------------------------------|----------------------------------|
| ΔB _{VDSS} ΔT _J loss loss On Chara V _{GS(th)} ΔV _{GS(th)} | Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics (Note 2) | $I_D = -250\mu$ A, referenced to 25°C $V_{DS} = -24V, V_{GS} = 0V$ | -30 | | | |
| $\frac{\Delta B_{VDSS}}{\Delta T_J}$ $\frac{I_{DSS}}{I_{GSS}}$ On Charace $\frac{V_{GS(th)}}{\Delta V_{GS(th)}}$ | Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics (Note 2) | $I_D = -250\mu$ A, referenced to 25°C $V_{DS} = -24V, V_{GS} = 0V$ | | | | V |
| I _{DSS} I _{GSS} On Chara V _{GS(th)} ΔV _{GS(th)} | Gate to Source Leakage Current cteristics (Note 2) | | | -20 | | mV/°C |
| I _{GSS} On Charac V _{GS(th)} ΔV _{GS(th)} | cteristics (Note 2) | | - | | -1 | μA |
| $V_{GS(th)}$ $\Delta V_{GS(th)}$ | | 1 | | | ±10 | μA |
| $V_{GS(th)}$ $\Delta V_{GS(th)}$ | | | | | | |
| $\Delta V_{GS(th)}$ | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, I_{D} = -250 \mu A$ | -1 | -1.9 | -3 | V |
| | Gate to Source Threshold Voltage Temperature Coefficient | $I_D = -250 \mu A$, referenced to $25^{\circ}C$ | | 8.1 | | mV/°C |
| | | V _{GS} = -10V , I _D = -14.5A | | 6.5 | 7.8 | |
| r | Drain to Source On Besistance | $V_{GS} = -4.5V, I_D = -12A$ | | 9.6 | 12 | |
| r _{DS(on)} | Drain to Source On Resistance | $V_{GS} = -10V, I_D = -14.5A$ $T_J = 125^{\circ}C$ | | 9.7 | 12 | - mΩ |
| 9 _{FS} | Forward Transconductance | V _{DS} = -5V, I _D = -14.5A | | 60 | | S |
| | Characteristics | 1 | | | | |
| C _{iss} | Input Capacitance | | | 3500 | 4700 | pF |
| C _{oss} | Output Capacitance | $V_{DS} = -15V, V_{GS} = 0V,$ | | 600 | 800 | pF |
| C _{rss} | Reverse Transfer Capacitance | f = 1.0MHz | | 600 | 900 | pF |
| | Characteristics (Note 2) | | | | | |
| e milening | | | | | | |
| t _{d(on)} | Turn-On Delay Time | | | 14 | 26 | ns |
| | Turn-On Delay Time Rise Time | V _{DD} = -15V, I _D = -1A | | 14 16 | 26 29 | ns ns |
| t _r | Rise Time | V _{DD} = -15V, I _D = -1A -V _{GS} = -10V, R _{GS} = 6Ω | | | - | |
| t _r t _{d(off)} | , | | | 16 | 29 | ns |
| t _r t _{d(off)} t _f | Rise Time Turn-Off Delay Time | | | 16 225 | 29 36 | ns ns |
| t _r t _{d(off)} t _f Q _g | Rise Time Turn-Off Delay Time Fall Time | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$ | | 16 225 105 | 29 36 167 | ns ns ns |
| t _r t _{d(off)} t _f Q _g Q _g | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ | | 16 225 105 88 | 29 36 167 124 | ns ns ns nC |
| t _r t _{d(off)} t _f Q _g Q _g Q _{gs} | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$ | | 16 225 105 88 46 | 29 36 167 124 | ns ns nS nC nC |
| t _r t _{d(off)} t _f Q _g Q _g Q _{gs} Q _{gd} | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ | | 16 225 105 88 46 8 | 29 36 167 124 | ns ns nC nC nC |
| t _r t _{d(off)} C _g C _g C _{gs} C _{gg} C _{gg} Drain-Sou | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge urce Diode Characteristics | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_D = -14.5A$ | | 16 225 105 88 46 8 | 29 36 167 124 | ns ns nC nC nC |
| t _r t _{d(off)} Q _g Q _g Q _{gs} Q _{gd} Drain-Sou V _{SD} | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_D = -14.5A$ | | 16 225 105 88 46 8 23.5 | 29 36 167 124 65 | ns ns nC nC nC nC |
| $\frac{t_{d(on)}}{t_r}$ $\frac{t_{d(off)}}{t_f}$ | Rise Time Turn-Off Delay Time Fall Time | $V_{GS} = -10V, R_{GS} = 6\Omega$ | | 16 225 105 | 29 36 167 | |
| t _r t _{d(off)} t _f Q _g Q _g Q _{gs} Q _{gd} | Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge Ince Diode Characteristics Source to Drain Diode Forward Voltage | $V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_{D} = -14.5A$ $V_{GS} = 0V, I_{S} = -2.1A$ | | 16 225 105 88 46 8 23.5 | 29 36 167 124 65 -1.2 | ns ns nC nC nC v |

Scale 1 : 1 on letter size paper

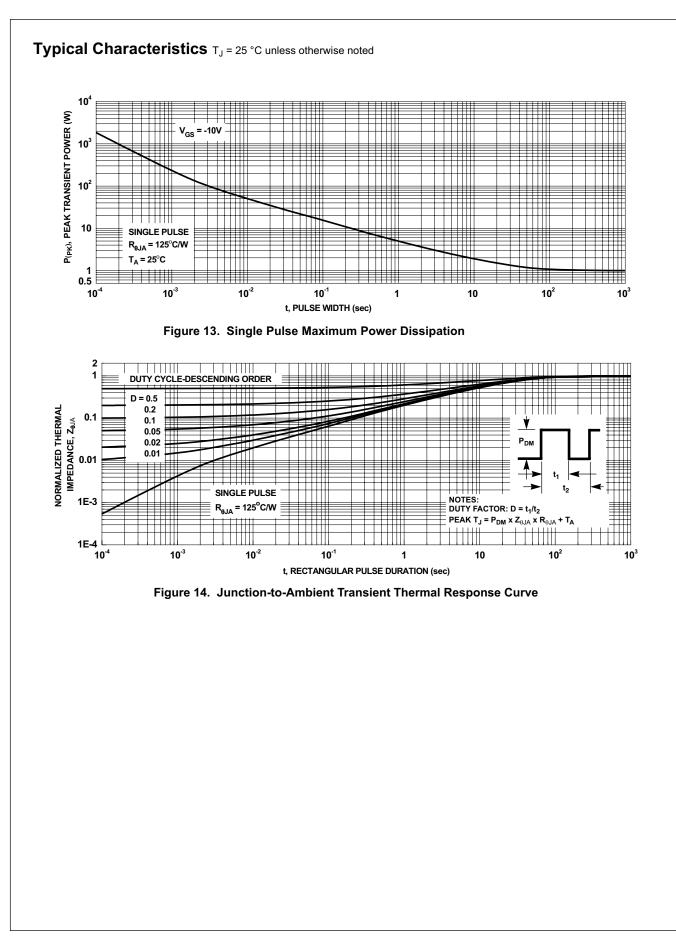
Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%.
 The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



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